## Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/579,467	Reexamination SHUTOU, SHUN:	SUKE
Examiner	Art Unit	
CHARLES CHANG	2883	Page 1 of 1

## U.S. PATENT DOCUMENTS

	U.S. PATERT DOGGMENTS				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0180916 A1	12-2002	Schadt et al.	349/117
*	В	US-6,608,661 B1	08-2003	Schadt et al.	349/124
*	С	US-6,734,936 B1	05-2004	Schadt et al.	349/117
*	D	US-6,778,242 B1	08-2004	Murayama et al.	349/117
	Е	US-			
	F	US-			
	G	US-		-	
	Н	US-		-	
		US-			
	J	US-			
	К	US-			
	L	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON DATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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